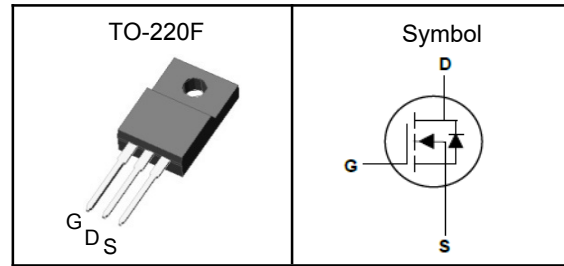


N-Channel Enhancement Mode MOSFET

Features

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant
- 100% UIS and Rg Tested

Pin Description



Applications

- Power Management in Desktop Computer
- DC/DC Converters

V_{DSS}	400	V
$R_{DS(ON)-Typ}$	0.22	Ω
I_D	19	A

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	400	V
V_{GSS}	Gate-Source Voltage	± 30	V
T_J	Maximum Junction Temperature	-55 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
E_{AS}	Single Pulse Avalanche Energy ^③	720	mJ
$I_{DM}^{①}$	Pulse Drain Current Tested	76	A
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	A
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	W

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ^① (Max)	62.5	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case ^①	2.86	$^\circ\text{C}/\text{W}$

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150 $^\circ\text{C}$.

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.



N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^{\circ}\text{C}$, Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	400	---	---	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=400V, V_{GS}=0V$	---	---	1	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	---	4	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 30V, V_{DS}=0V$	---	---	± 100	nA
$R_{DS(on)}$	Drain-Source On-state Resistance	$V_{GS}=10V, I_D=9.5A$	---	0.22	0.28	Ω
Dynamic Characteristics ^⑤						
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=25V,$ Freq.=1MHz	---	1900	---	pF
C_{oss}	Output Capacitance		---	200	---	
C_{rss}	Reverse Transfer Capacitance		---	12	---	
$T_{d(on)}$	Turn-on Delay Time	$V_{DD}=200V,$ $V_{GS}=25\Omega, I_D=19A$	---	21	---	nS
T_r	Turn-on Rise Time		---	36	---	
$T_{d(off)}$	Turn-off Delay Time		---	55	---	
T_f	Turn-off Fall Time		---	52	---	
Q_g	Total Gate Charge	$V_{DD}=320V, V_{GS}=10V,$ $I_D=19A$	---	42	---	nC
Q_{gs}	Gate-Source Charge		---	9	---	
Q_{gd}	Gate-Drain Charge		---	17	---	
Source-Drain Characteristics ($T_J=25^{\circ}\text{C}$)						
V_{SD}	Diode Forward Voltage _z	$V_{GS}=0V, I_S=19A, T_J=25^{\circ}\text{C}$	---	---	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS}=0V, I_S=19A,$ $di/dt=100A/\mu s, T_J=25^{\circ}\text{C}$	---	340	---	nS
Q_{rr}	Reverse Recovery Charge		---	3.1	---	μC

Note ④ : Pulse test (pulse width \leq 300us, duty cycle \leq 2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Enhancement Mode MOSFET

Typical Characteristics

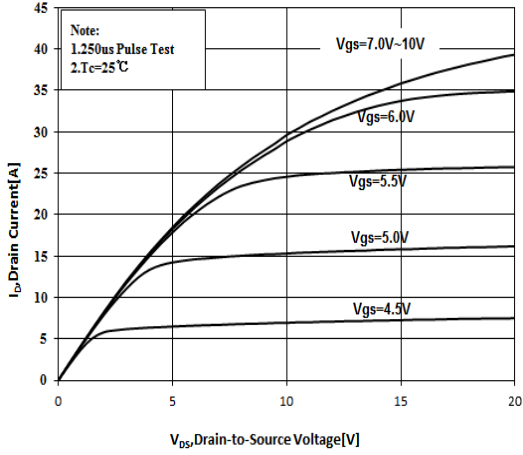


Figure 1 Typical Output Characteristics

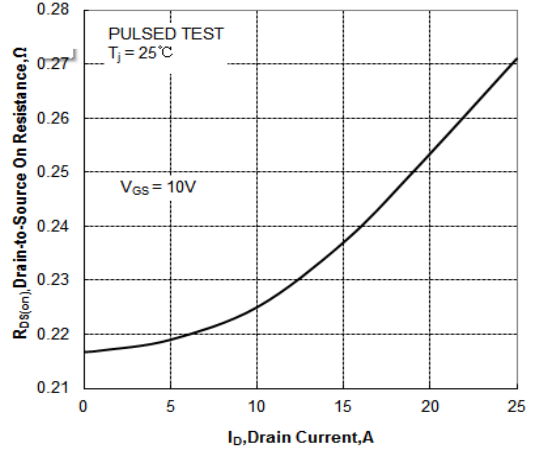


Figure 2 Typical Drain to Source ON Resistance vs Drain Current

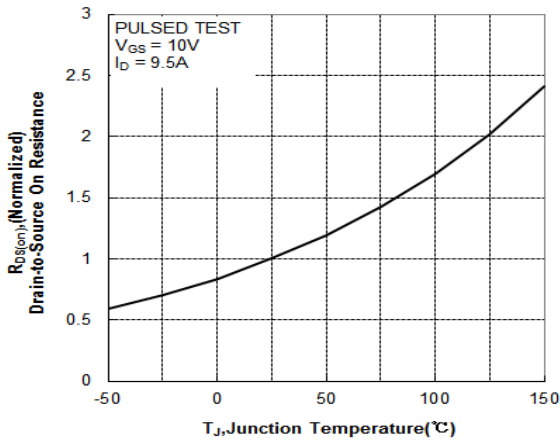


Figure 3 Typical Drain to Source on Resistance vs Junction Temperature

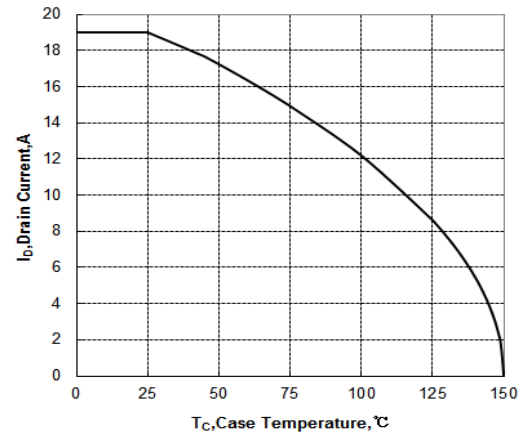


Figure 4 Maximum Continuous Drain Current vs Case Temperature

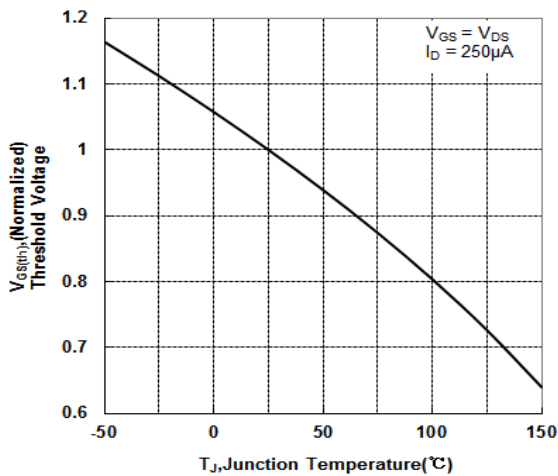


Figure 5 Typical Threshold Voltage vs Junction Temperature

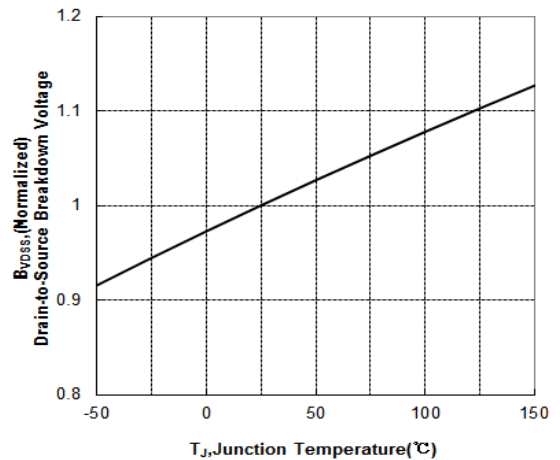


Figure 6 Typical Breakdown Voltage vs Junction Temperature

N-Channel Enhancement Mode MOSFET

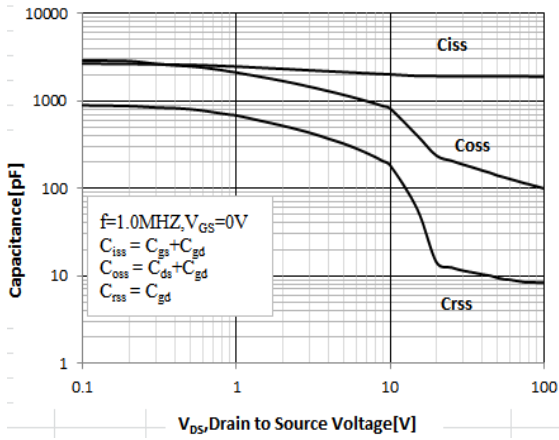


Figure 7 Typical Capacitance vs Drain to Source Voltage

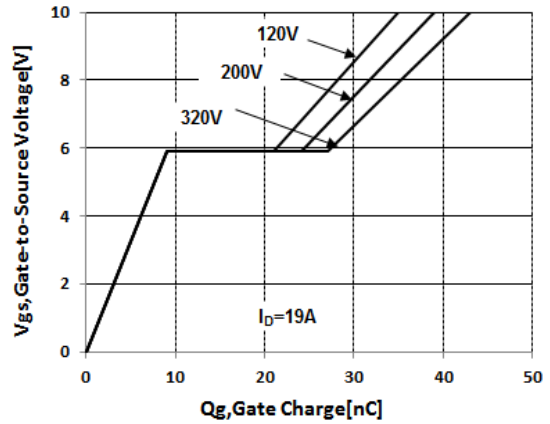


Figure 8 Typical Gate Charge vs Gate to Source Voltage

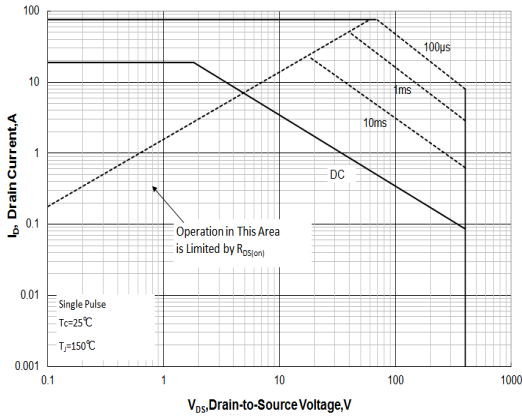


Figure 9 Maximum Safe Operation Area

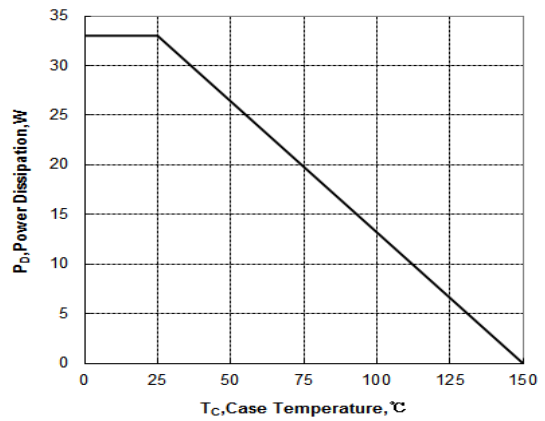


Figure 10 Maximum Power dissipation vs Case Temperature

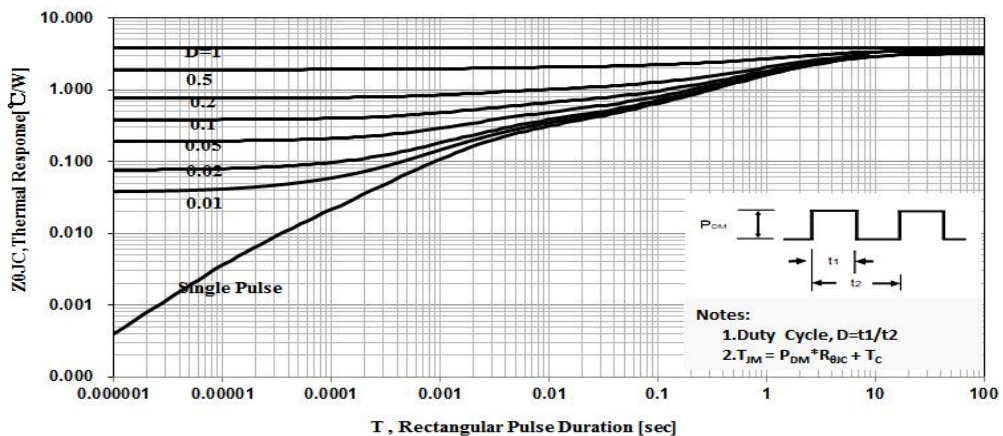


Figure 11 Maximum Effective Thermal Impedance , Junction to Case

N-Channel Enhancement Mode MOSFET
TO-220F Package Outline Data
